

FCC ID: 2ALXX-SPOON

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] * [\sqrt{f(\text{GHz})}] \leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where}$$

$f(\text{GHz})$ is the RF channel transmit frequency in GHz;

Power and distance are rounded to the nearest mW and mm before calculation;

The result is rounded to one decimal place for comparison;

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm

and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

We use 5mm as separation distance to calculated.

Bluetooth DSS:

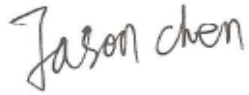
Transmit Frequency (GHz)	Mode	Measured Power (dBm)	Tune-up power (dBm)	Max tune-up power(dBm)	Result calculation	1g SAR
2.402	GFSK	2.91	2±1	3	0.6185	3
2.441		2.85	2±1	3	0.6235	3
2.48		2.02	2±1	3	0.6284	3
2.402	$\pi/4$ -DQPSK	1.63	1±1	2	0.4913	3
2.441		1.79	1±1	2	0.4952	3
2.48		1.15	1±1	2	0.4992	3
2.402	8DPSK	2.05	2±1	3	0.6185	3
2.441		2.11	2±1	3	0.6235	3
2.48		1.45	2±1	3	0.6284	3

Bluetooth DTS:

Transmit Frequency (GHz)	Mode	Measured Power (dBm)	Tune-up power (dBm)	Max tune-up power(dBm)	Result calculation	1g SAR
2.402	GFSK	3.08	3±1	4	0.7786	3
2.44		3.08	3±1	4	0.7847	3
2.48		2.3	3±1	4	0.7911	3

Conclusion:

For the max result : $0.7911 \leq 3.0$ for 1g SAR, No SAR is required.

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